Diagnostic Manager™ Series ScanXY

Scan Chain Mismatch Diagnosis in the Physical Domain

ScanXY Features:

- ***Physically view XY location of scan cell mismatches***
- ***No 3rd Party Intervention – Need only results of tester failures***
- ***Highlight physical location and stitch ordering of scan chains***
- ***View, manage and stack multiple test results from devices, wafers to shorten time-to-yield***
- ***Validates integrity and completeness of design before release to manufacturing***

ScanXY, The first product in the Teseda Diagnostic Manager™ series, quickly links structural test mismatch data to its physical domain for rapid analysis and diagnosis of defects and hot spots.

The incorporation of scan-based testing drives the need for scan-based diagnostic software provided in the Teseda Diagnostic Manager™ Series. **ScanXY** bridges design, test, manufacturing and failure analysis by providing the logical to physical correlation using the benefit of your scan architecture.

ScanXY interprets physical design information and failure files and highlights reported mismatches of failed test results to the capturing scan cell in a physical XY location on the die. No other third party tools are required to view and analyze results.

Immediately begin yield learning with single or stacked results on volumes of failing structural test data from multiple devices or die on a wafer. **ScanXY** is integrated with the Teseda WorkBench™ so it easily imports results from the Teseda V500 Series platforms or any ATE hosting the TWB. Also available in stand alone to read in EDA or ATE failure files formatted from your test database or ATE.

KEY BENEFITS:

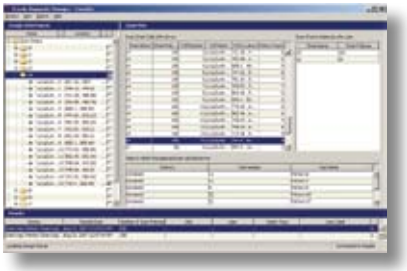
- Allows Design and FA to communicate failing data in both structural language and XY location
- Speeds analysis of failing devices – hours instead of days
- Allows identification of Failure Trends based on analysis of multiple tests
- Works with any EDA DFT diagnostic flows and supports all EDA failure file formats
- Directly links to the Teseda WorkBench
- Adds verification check to ensure all files are included in design package

Highlights scan cell mismatches and stitching order

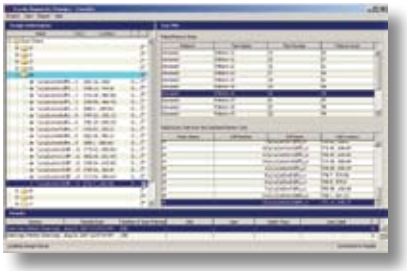
ScanXY diagnostic software capability functions in any diagnostic environment

Teseda's **ScanXY** with its easy-to-use graphical user interface with point-and-click commands lends itself well to design, test, production and failure analysis engineers. **ScanXY** is integrated into the Teseda TWB environment or can be used stand alone for any diagnosis environment. Hardware platform and test software independent, **ScanXY** can be customized to support any failure file formats.

Graphically view physical locations of mismatches

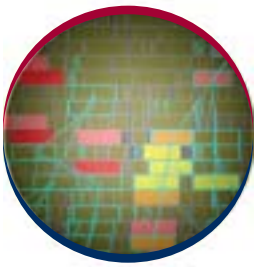


Reports the failing pattern from the scan cell mismatch

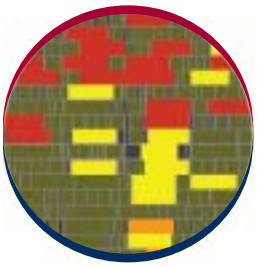


Determine the mismatching scan cell based on pattern

Stop analyzing scan failures one device at a time. Teseda's **ScanXY** enables you to increase speed to yield ramp-up with stackable viewing of multiple devices. Whether you're testing multiple packaged parts or die on wafers, view all your stacked device test mismatches all at once.



Teseda's **ScanXY** viewing features zooms you in and out to any scan cell. Quickly see mismatches on any scan cell based on test failure. Highlight any and all scan chains in a single click to see scan ordering and XY locations.



Teseda's **ScanXY** is designed for test engineering, production and failure analysis and is offered stand alone or integrated with the Teseda WorkBench™. Diagnostic software plug and play for any diagnostic environment.

ScanXY Functional Overview

Physical design data
- Industry Standard Formats

Import Scan Information
- STIL
- EDA DFT Scan Chain/Cell Reports

Imported information
- Signal names, scan structures, test data, structural test mismatches

Test results views and summaries:
- Scan chains/cells reporting mismatch
- Shmoo Plot, Chain Plot, Test Plot, Color Coded Mapping, Failure Reports

Workstation Requirements
- Windows, Unix, Linux
  1GB RAM minimum
  1GHz minimum; 2GHz recommended

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Teseda provides a unifying software and hardware environment that allows multiple engineering disciplines to accelerate the delivery of first silicon.

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